

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/791,299	HOSMER ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
Justin Y. Lee	2617	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner